## Application/Control No. Applicant(s)/Patent Under Reexamination KIKUCHI ET AL. 09/829,876 Notice of References Cited Examiner Art Unit Page 1 of 1 Douglas W Owens 2811

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			-
	D	US-			
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## **NON-PATENT DOCUMENTS**

* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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